

# Jet smearing - status

## UHH-CMS SUSY Meeting

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GEFÖRDERT VOM

Bundesministerium  
für Bildung  
und Forschung

# Input sample from ToyMC

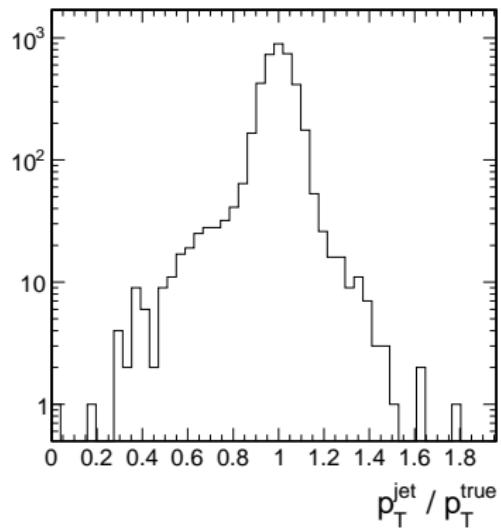
Disclaimer: **All shown results from SmearCore framework**

- Generation of dijet and  $\gamma$ -jet events
- Response probability density as sum of two Gaussians

$$p(R) = c \cdot G_0(R; 1, \sigma_0) + (1 - c) \cdot G_1(R; \mu_1, \sigma_1)$$

where  $c = 0.96$ ,  $\sigma_0 = 0.06$ ,  
 $\mu_1 = 0.9$ , and  $\sigma_1 = 0.25$

- $p_T^{\text{true}}$ -spectrum flat or powerlaw
- Similar to response from Summer08 dijet sample with  
 $600 < \hat{p}_T < 800$  GeV



$$\frac{p_{\text{jet}}}{p_T} / p_T^{\text{true}}$$

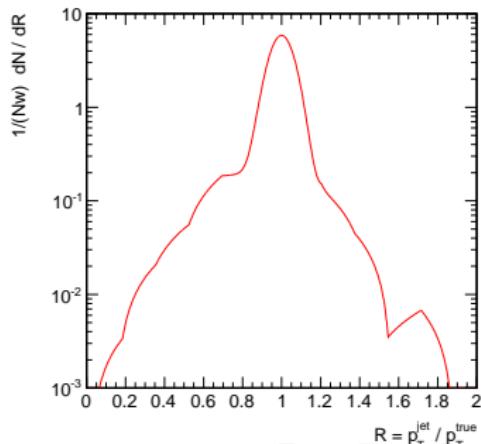
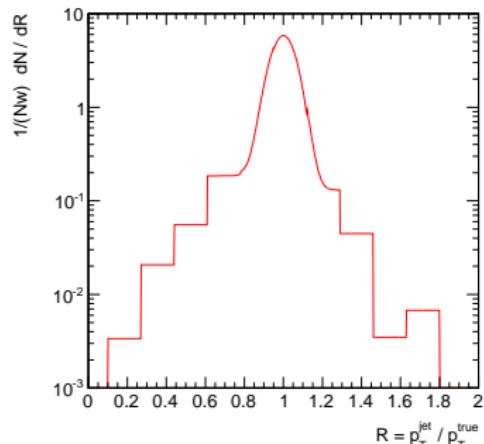
# Fitted response: Gauss + step function

- Response probability density

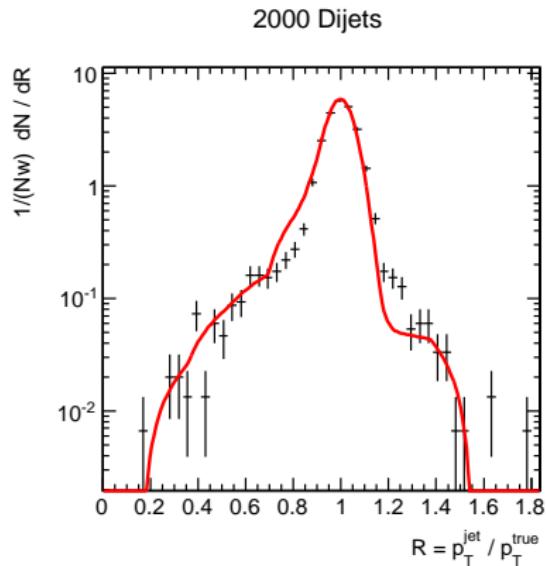
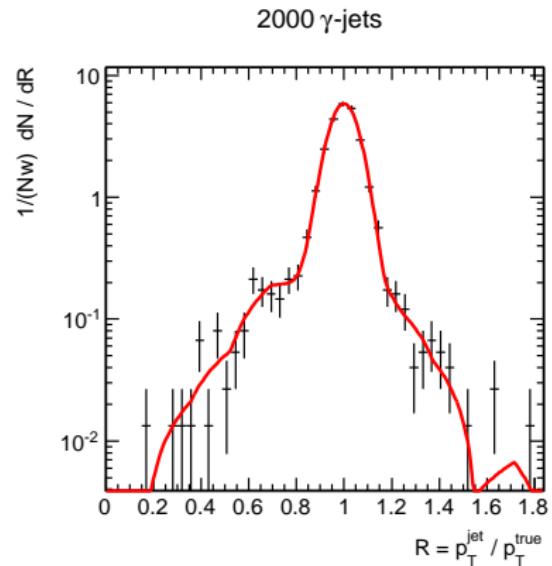
$$p(R) = c \cdot G(R; 1, \sigma) + (1 - c) \cdot f_{10}(R; \mathbf{b})$$

- $f_{10}$  step function

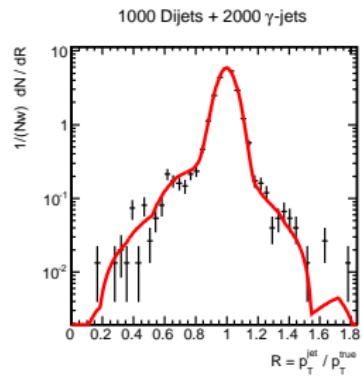
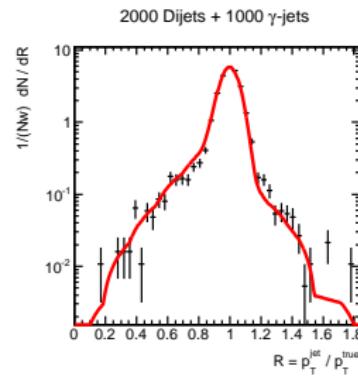
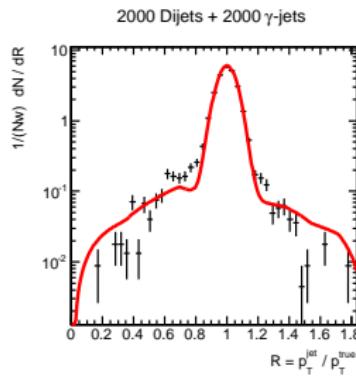
- ▶ 10 bins in  $0.1 < R < 1.8$
- ▶ Bin content  $b_i \geq 0$  by construction
- ▶ Quadratically divergent penalty term to guide minimization
- ▶ Actual  $f_{10}(R)$  is linear interpolation of bin contents



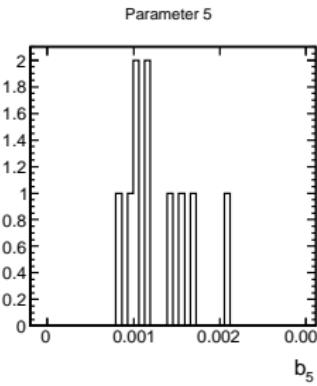
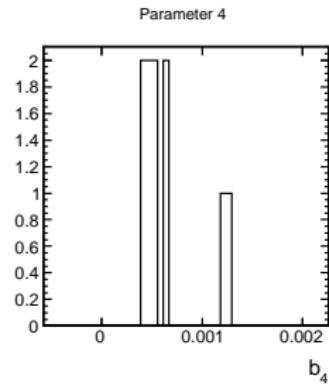
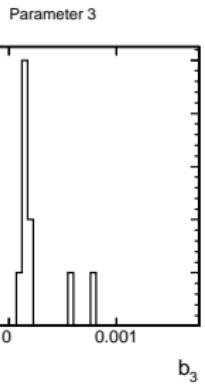
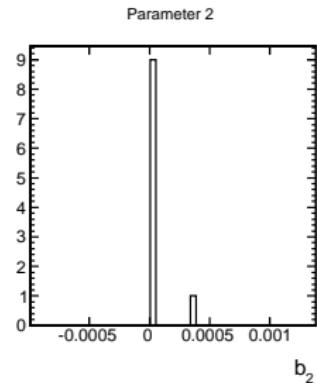
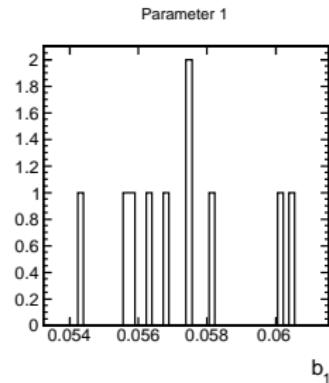
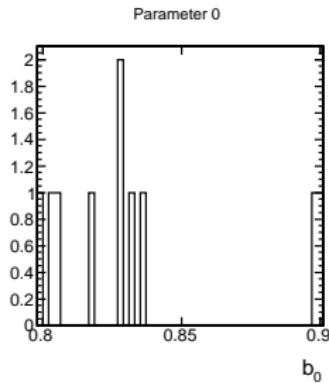
# Fit results: separate fits for dijet and $\gamma$ -jet events



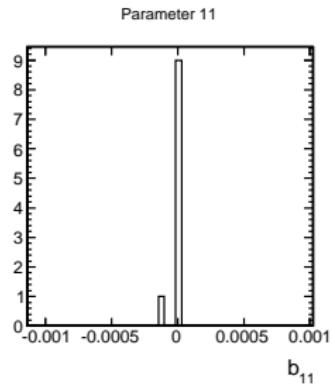
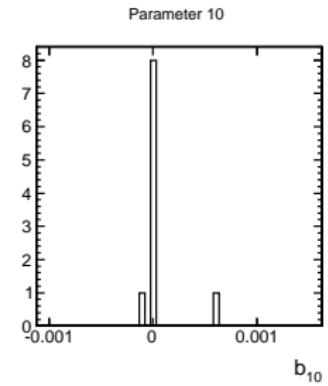
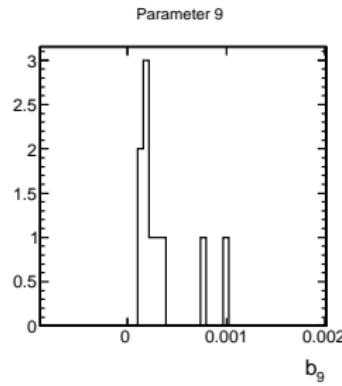
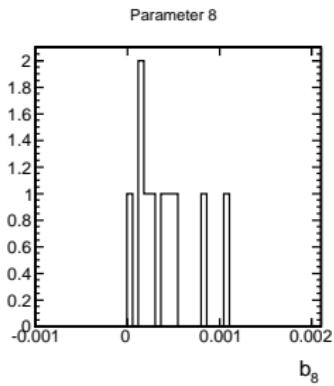
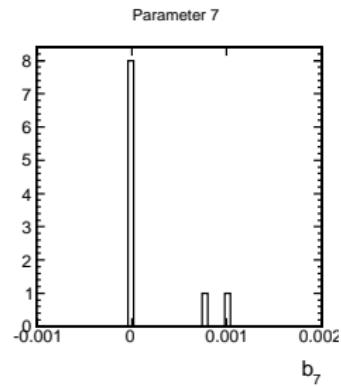
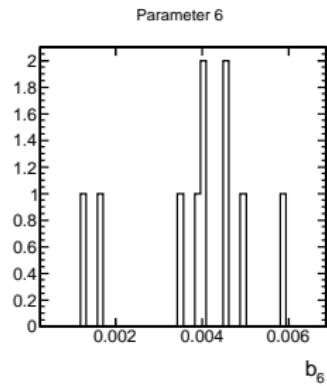
# Fit results: combined fits for dijet and $\gamma$ -jet events



# Fit stability (successive fit of 10 different samples)

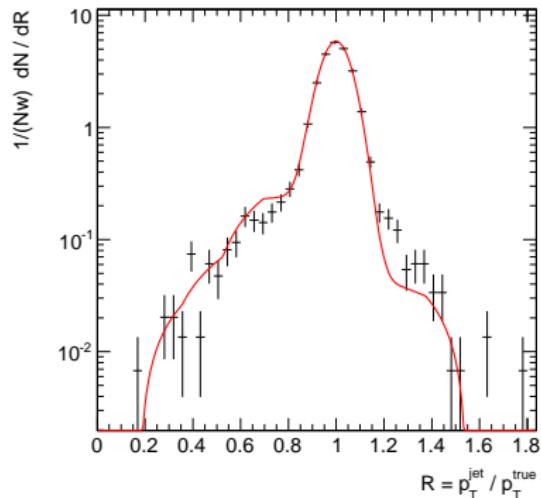
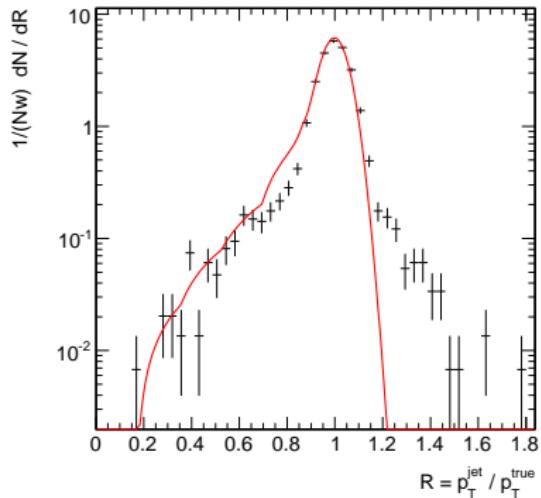


# Fit stability (successive fit of 10 different samples)



# Fit results: separate fits for dijet and $\gamma$ -jet events

- $p_T^{true}$ -spectrum falling as  $1/x^5$  and  $p_T^{true} > 100$  GeV



- Start parameters like before  
(reasonable Gauss + flat step)

- Start parameters from previous fit with flat spectrum

# Outlook

- Improvement of stability of fit for falling  $p_T$  spectrum
- Study of influence of functional form of  $p_T$  spectrum on fit (systematic errors)
- Fit of different  $\hat{p}_T$  bins and study of parameter variation
- Study of influence of cuts on measured  $p_T$  on fit